

Notice of References Cited	Application/Control No. 10/741,490	Applicant(s)/Patent Under Reexamination POTEMPA, EDWARD M.	
	Examiner Jeff Natalini	Art Unit 2858	Page 1 of 1

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NON-PATENT DOCUMENTS

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	U	Ichimura et al. "Measuring the Internal Resistance of a Cell in Assembled Batteries", 1996 IEEE, pgs 784-791.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.